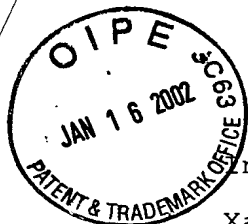


2877



PATENTS
7105
K. Jones
2/11/02

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Xavier Jean-François LEVECQ et al.

Serial No. 09/889,307

GROUP 2877

Filed November 2, 2001

Examiner Unassigned

METHOD AND DEVICE FOR ANALYZING A HIGHLY DYNAMIC WAVEFRONT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Washington, D.C. 20231

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed sheet.

A concise explanation of the relevance of these items is that these references were cited by the French Patent Office in the corresponding French application Serial No. 9900366 filed January 15, 1999 and in the International Search Report in the corresponding international application Serial No. PCT/FR00/00063 filed January 14, 2000. Copies of the French Search Report and International Search Report in which they were cited are attached hereto.

Respectfully submitted,

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By

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January 16, 2002

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09/889,307

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use several sheets if necessary)

37 CFR 1.98(b)

APPLICANT
Xavier Jean-François LEVECQ et al.

FILING DATE
November 2, 2001

GROUP
2877

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	PATENT NUMBER	ISSUE DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
AA						
AB						
AC						
AD						
AE						
AF						

FOREIGN PATENT OR PUBLISHED FOREIGN PATENT APPLICATION

	DOCUMENT NO.	PUBL. DATE	COUNTRY OR PATENT OFFICE	CLASS	SUB CLASS	TRANSLATION YES
AI	197 05 119 A1	08/98	DE			With English summary
AJ						
AK						
AL						
AM						
AN						

OTHER DOCUMENTS (Including Author, Title, Date, Relevant Pages, Place of Publication)

AT	Michael C. Roggemann et al., "Algorithm to Increase the Largest Aberration that Can be Reconstructed from Hartman Sensor Measurements," <u>APPLIED OPTICS</u> , v. 37, 1998, PP. 4321-4329.
AU	
AV	
AW	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.